

Notice of References Cited	Application/Control No. 10/559,527		Applicant(s)/Patent Under Reexamination SHINKAI ET AL.	
	Examiner ANEETA PATANKAR		Art Unit 4134	Page 1 of 1

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*	A	US-2002/0097645	07-2002	Mikawa, Takuma	369/47.1
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NON-PATENT DOCUMENTS

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